

## New Compact SIMS at 61st AVS Visit us on Booth 311

Hidden is pleased to announce they will be exhibiting the **New Compact SIMS**, a design breakthrough for surface analysis, at **61st AVS 9-14 November 2014**, Baltimore MD, USA. **Visit us on Booth 311**. The Compact SIMS tool is designed for fast and easy characterisation of layer structures, surface contamination and impurities with sensitive detection of positive ions being assisted by the oxygen primary ion beam and provides isotopic sensitivity across the entire periodic table. The ion gun geometry is optimised to be ideal for nanometre depth resolution and near surface analysis.

A rotary carousel enables 10 samples to be simultaneously loaded for measurement into the dry-pumped vacuum chamber. The instrument has a small footprint and is exceptionally easy to use, it boasts the same control software and ion gun system as the fully featured Hidden SIMS Workstation family, providing depth profiles, 3D and 2D images and mass spectral data. The MAXIM-600P detector is based around the highly reliable Hidden 6mm triple quadrupole mass filter with pulse ion detection. An electron gun option is available for analysis of insulating samples.

In addition to SIMS, the Compact SIMS has an SNMS facility that is useful for quantification of high concentration elements, such as alloys.

### Applications:

- Solar cells
- Glass coatings
- Metallic thin films

### Features:

- Small footprint
- Easy user friendly layout
- Positive SIMS and SNMS
- Depth Profiling
- 3D characterisation and imaging
- Mass spectra
- Isotopic analysis
- Analysis on the nanometre scale



**New Compact SIMS**

For further information on this or any other Hidden Analytical products visit the Hidden Analytical **Booth 311** at 61st AVS or contact Hidden Analytical at: [info@hidden.co.uk](mailto:info@hidden.co.uk) or visit the main website at [www.HiddenAnalytical.com](http://www.HiddenAnalytical.com).

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